Notice of References Cited

Application/Control No. 10/717,496	Applicant(s)/Patent Under Reexamination SAINT ETIENNE ET AL.	
Examiner	Art Unit	
Kenan Cehic	2616	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,381,404 A	01-1995	Sugano et al.	370/238
*	В	US-5,565,924 A	10-1996	Haskell et al.	348/423.1
*	С	US-2002/0181506 A1	12-2002	Loguinov, Dmitri	370/473
*	D	US-6,560,230 B1	05-2003	Li et al.	370/395.42
*	E	US-6,735,192 B1	05-2004	Fried et al.	370/352
*	F	US-2004/0233931 A1	11-2004	Cohen, Ron	370/468
*	G	US-6,850,491 B1	02-2005	Firoiu et al.	370/235
*	Н	US-6,937,562 B2	08-2005	Farley et al.	370/230
*	-	US-6,954,426 B2	10-2005	Suominen, Jukka	370/230
*	J	US-7,072,295 B1	07-2006	Benson et al.	370/230
*	К	US-7,116,639 B1	10-2006	Gail et al.	370/252
*	L	US-7,164,680 B2	01-2007	Loguinov, Dmitri	370/394
	М	US-		·	

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N			·		
	0					
	Р					
	Q					
	R					
	s		,			
	т	•			·	

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	v				
	w				
	x				

^{*}A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.